

## FERROMAGNETIC CONTACTS ON SINGLE WALL CARBON NANOTUBES

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We are investigating the influence of spin degree of freedom on electrical transport measurements in ferromagnetically contacted Single Wall Carbon Nanotubes (SWCNT) in presence of an external magnetic field.

On a wafer with predefined alignment markers SWCNT were grown by chemical vapor deposition (CVD). After their positional detection w.r.t. these markers under an atomic force microscope (AFM) ferromagnetic  $\text{Pd}_{1-x}\text{Fe}_x$  contacts ( $x=0.2, \dots, 0.5$ ) were written using electron beam lithography. Two additional non-ferromagnetic contacts allow four-point measurement geometries. On Si/SiO<sub>2</sub> samples the substrate serves as a backgate.

An external magnetic field  $B_{\parallel}$  along their magnetic easy axis governs the relative magnetization configuration of the first  $\text{Pd}_{1-x}\text{Fe}_x$  contact (spin injector) and the second  $\text{Pd}_{1-x}\text{Fe}_x$  contact (spin detector) as, through choice of different aspect ratios, the contacts have different coercive fields. Possible configurations are parallel or antiparallel.

By means of Lorentz microscopy in a tunnelling scanning microscope (TEM), the magnetization switching behaviour of contacted SWCNT prepared on thin (30nm) Si<sub>3</sub>N<sub>4</sub> membranes will be observed in-situ.